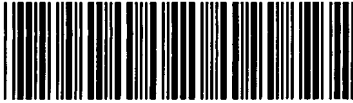


**Search Notes**

Application/Control No.

10/623,657

Examiner

TAN X. DINH

Applicant(s)/Patent under  
Reexamination

ISHI ET AL.

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (see search history printout)	7/16/2007	T.D